

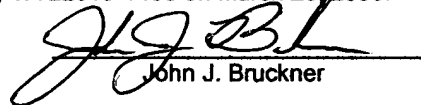
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE	
<b>SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>	Atty. Docket No. <b>UBAT1510</b>
Applicant <b>Gregory R. Hanson et al.</b>	
Application Number <b>10/649,251</b>	Filed <b>August 26, 2003</b>
For <b>Spatial Heterodyne Interferometry for Transmission (SHIFT) Measurements</b>	
Group Art Unit <b>2631</b>	Examiner <b>Unknown</b>

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**Certificate of Mailing Under 37 C.F.R. 1.8**

I hereby certify that this correspondence is being deposited with the U.S. Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on March 28, 2005.

  
John J. Bruckner

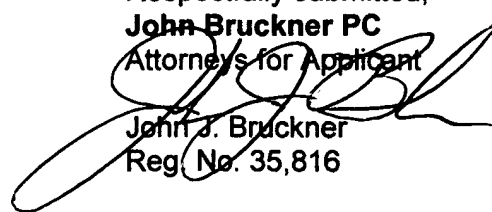
Applicants respectfully request, pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, that the art listed on the attached PTO-1449 form be considered and cited in the examination of the above-identified application. A copy of the art is enclosed for the convenience of the Examiner. Furthermore, pursuant to 37 C.F.R. §§ 1.97(g) and (h), no representation is made that a search has been made or that this art is material to patentability of the present application.

Copies of the reference(s) is(are) enclosed for the convenience of the Examiner. Applicant hereby states under 37 C.F.R. § 1.97 (e) that each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this information disclosure statement.

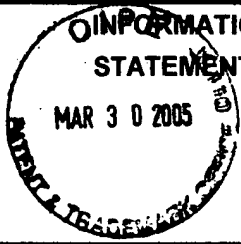
While Applicants believe no (further) fees are due, if any (further) fees are due, the Commissioner is hereby authorized to charge any fees or credit any overpayments to Deposit Account No. 50-3204 of John Bruckner PC.

Dated: Mar 28, '05  
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Respectfully submitted,  
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			Application Number		10/649,251			
			Filing Date		August 26, 2003			
			First Named Inventor		Gregory R. Hanson			
			Group Art Unit		2621			
			Examiner Name		Unknown			
Sheet 1		of 1		Attorney Docket Number		UBAT1510		
<b>NON-PATENT LITERATURE DOCUMENTS</b>								
		International Search Report and Written Opinion, PCT/US2004/027766, February 2, 2005.						
		Thomas C. E., et al. "Direct to digital holography for high aspect ratio inspection of semiconductor wafers" AIP Conference Proceedings, American Institute of Physics, New York, NY, US, no. 683, March 24, 2003, pages 254-270.						
		Cuche E., et al. "Simultaneous amplitude-contrast and quantitative phase-contrast microscopy by numerical reconstruction of Fresnel off-axis holograms: Applied Optics, Optical Society of America USA, vol. 38, no. 34, December 1, 1999, pages 6994-7001.						
		Cuche E., et al. "Spatial filtering for zero-order and twin-image elimination in digital off-axis holography" Applied Optics, Optical Society of America USA, vol. 39, no. 23, August 10, 2000, pages 4070-4075.						
		International Search Report and Written Opinion, PCT/US2004/027749, February 2, 2005.						
		Cuche E., et al. "Digital holography for quantitative phase-contrast imaging" Optical Letter, Optical Society of America, Washington, USA, vol. 24, no. 5, March 1, 1999, pages 291-293.						
		Schnars U., "Direct phase determination in hologram interferometry with use of digitally recorded holograms" Journal of the Optical Society of America - A, Optical Society of America, Washington, US, vol. 11, no. 7, July 1, 1994, pages 2011-2015.						
Examiner Signature					Date Considered			